

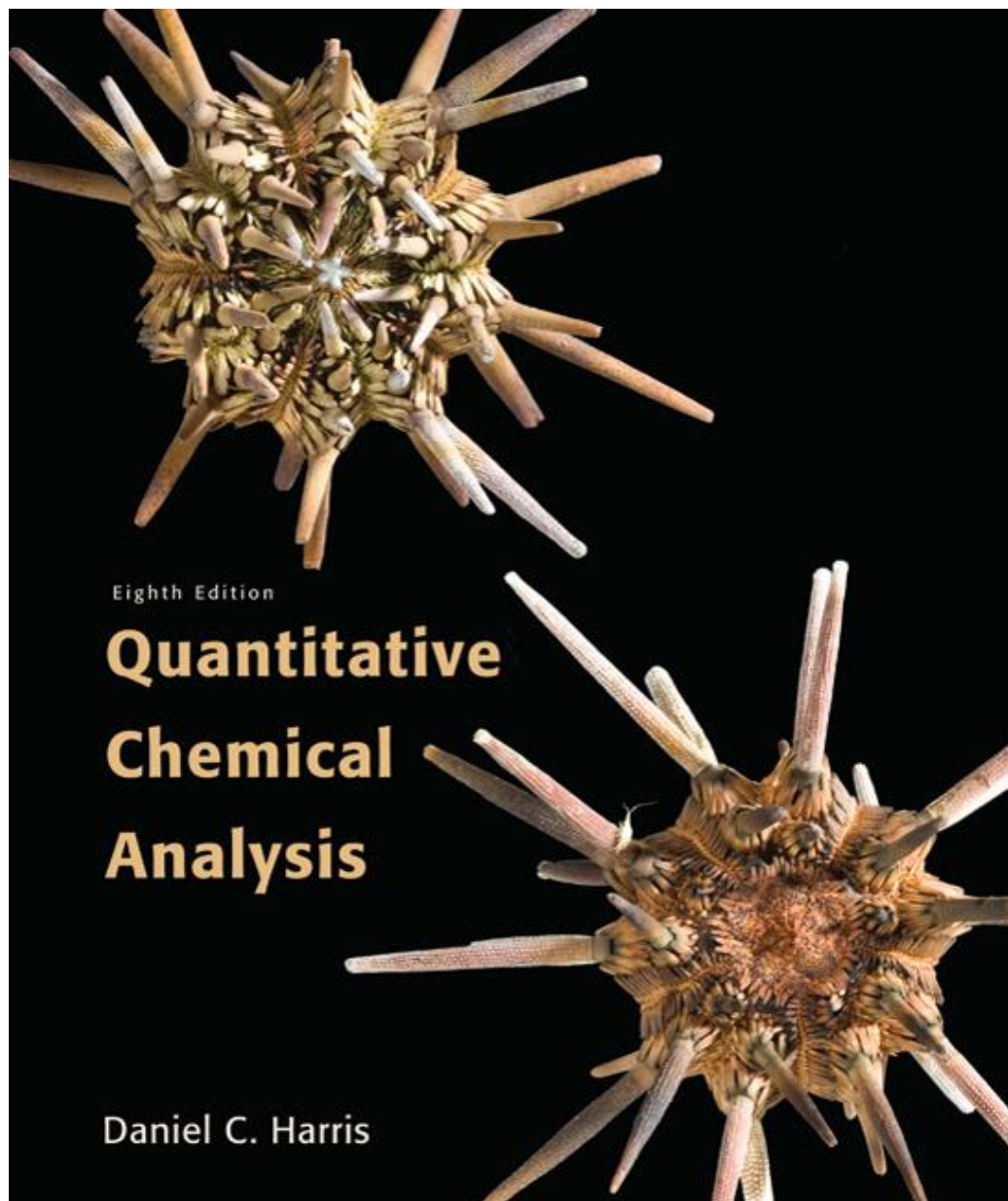
84.314

**Analytical Chemistry II
(Instrumental Analysis)**

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Eighth Edition

Quantitative Chemical Analysis

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Website

http://faculty.uml.edu/David_Ryan/84.314/

- **Syllabus = course description**
- **Schedule**
- **Materials = Lecture Slides,
Handouts, Videos of prior years**

Introduction

- **Basics of Instrumental Analysis**
 - **Properties Employed in Instrumental Methods**
 - **Numerical Criteria**
 - **Figures of Merit**

TABLE 1-1 Chemical and Physical Properties Employed in Instrumental Methods

Characteristic Properties	Instrumental Methods
Emission of radiation	Emission spectroscopy (X-ray, UV, visible, electron, Auger); fluorescence, phosphorescence, and luminescence (X-ray, UV, and visible)
Absorption of radiation	Spectrophotometry and photometry (X-ray, UV, visible, IR); photoacoustic spectroscopy; nuclear magnetic resonance and electron spin resonance spectroscopy
Scattering of radiation	Turbidimetry; nephelometry; Raman spectroscopy
Refraction of radiation	Refractometry; interferometry
Diffraction of radiation	X-Ray and electron diffraction methods
Rotation of radiation	Polarimetry; optical rotary dispersion; circular dichroism
Electrical potential	Potentiometry; chronopotentiometry
Electrical charge	Coulometry
Electrical current	Amperometry; polarography
Electrical resistance	Conductometry
Mass	Gravimetry (quartz crystal microbalance)
Mass-to-charge ratio	Mass spectrometry
Rate of reaction	Kinetic methods
Thermal characteristics	Thermal gravimetry and titrimetry; differential scanning calorimetry; differential thermal analyses; thermal conductometric methods
Radioactivity	Activation and isotope dilution methods

TABLE 1-3 Numerical Criteria for Selecting Analytical Methods

Criterion	Figure of Merit
1. Precision	Absolute standard deviation, relative standard deviation, coefficient of variation, variance
2. Bias	Absolute systematic error, relative systematic error
3. Sensitivity	Calibration sensitivity, analytical sensitivity
4. Detection limit (LOD)	Blank plus three times standard deviation of a blank
5. Concentration range	Concentration limit of quantitation (LOQ) to concentration limit of linearity (LOL)
6. Selectivity	Coefficient of selectivity

**TABLE 1-4 Other Characteristics
to Be Considered
in Method Choice**

1. Speed
2. Ease and convenience
3. Skill required of operator
4. Cost and availability of equipment
5. Per-sample cost

TABLE 1-5 Figures of Merit for Precision of Analytical Methods

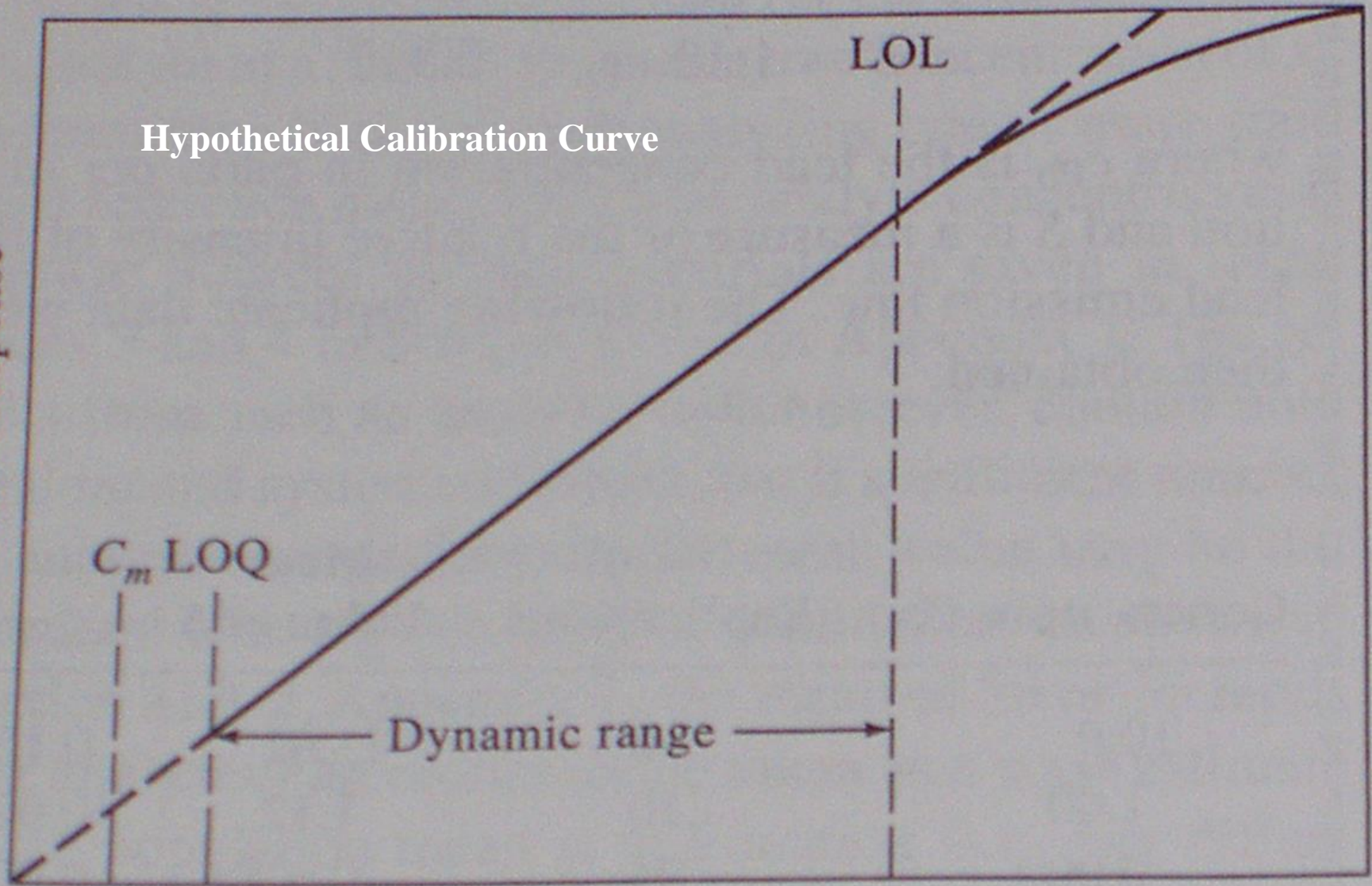
Terms	Definition*
Absolute standard deviation, s	$s = \sqrt{\frac{\sum_{i=1}^N (x_i - \bar{x})^2}{N - 1}}$
Relative standard deviation (RSD)	$\text{RSD} = \frac{s}{\bar{x}}$
Standard deviation of the mean, s_m	$s_m = s/\sqrt{N}$
Coefficient of variation, CV	$\text{CV} = \frac{s}{\bar{x}} \times 100\%$
Variance	s^2

* x_i = numerical value of the i th measurement.

$$\bar{x} = \text{mean of } N \text{ measurements} = \frac{\sum_{i=1}^N x_i}{N}$$

Hypothetical Calibration Curve

Instrument response



Concentration

Signals and Noise

➤ **Signal to Noise Ratio**

**All instrumental measurements
involve a signal**

**Unfortunately all signals have
noise present**

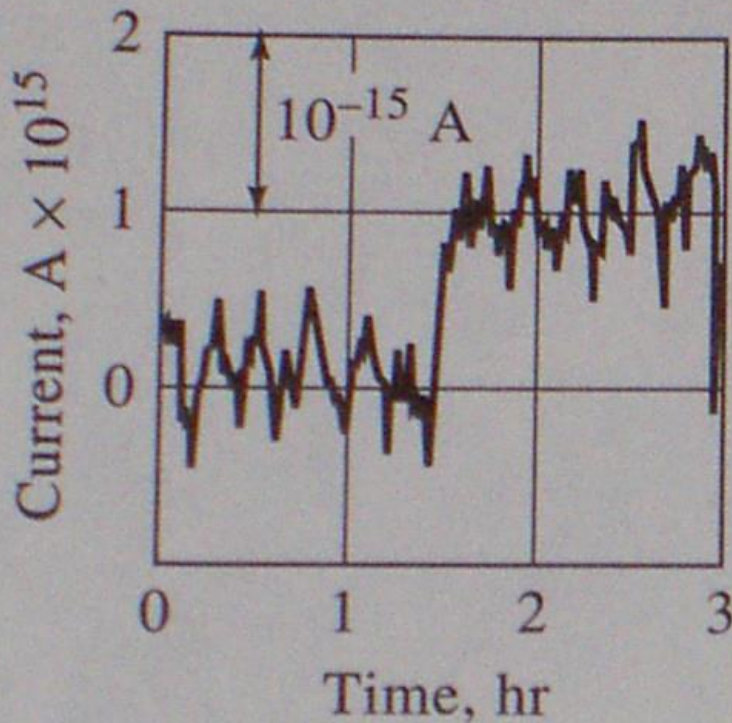
Sometimes the noise is large

**Sometimes it is so small you
can't see it**

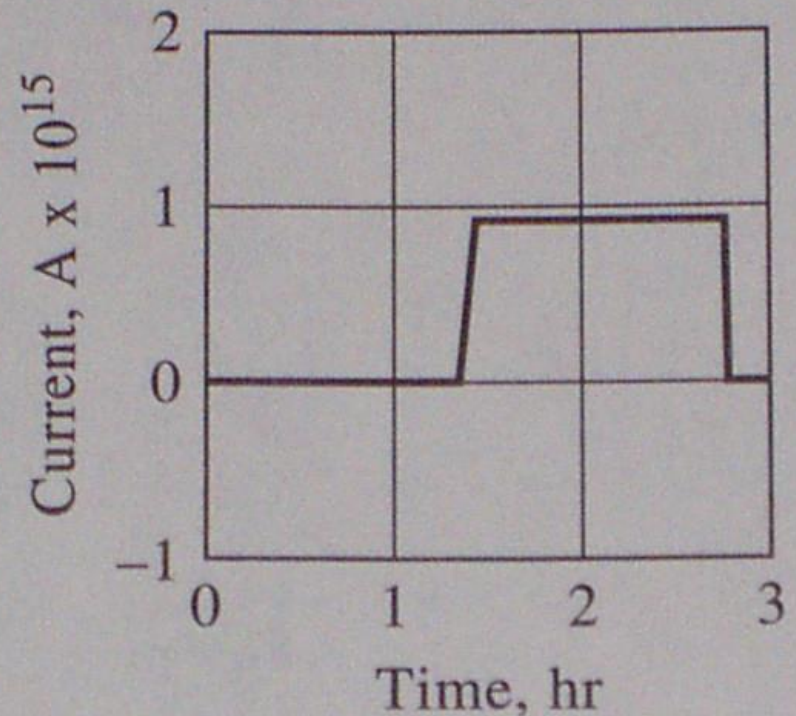
Current measurements

(a) with noise,

(b) with noise averaged out



(a)



(b)

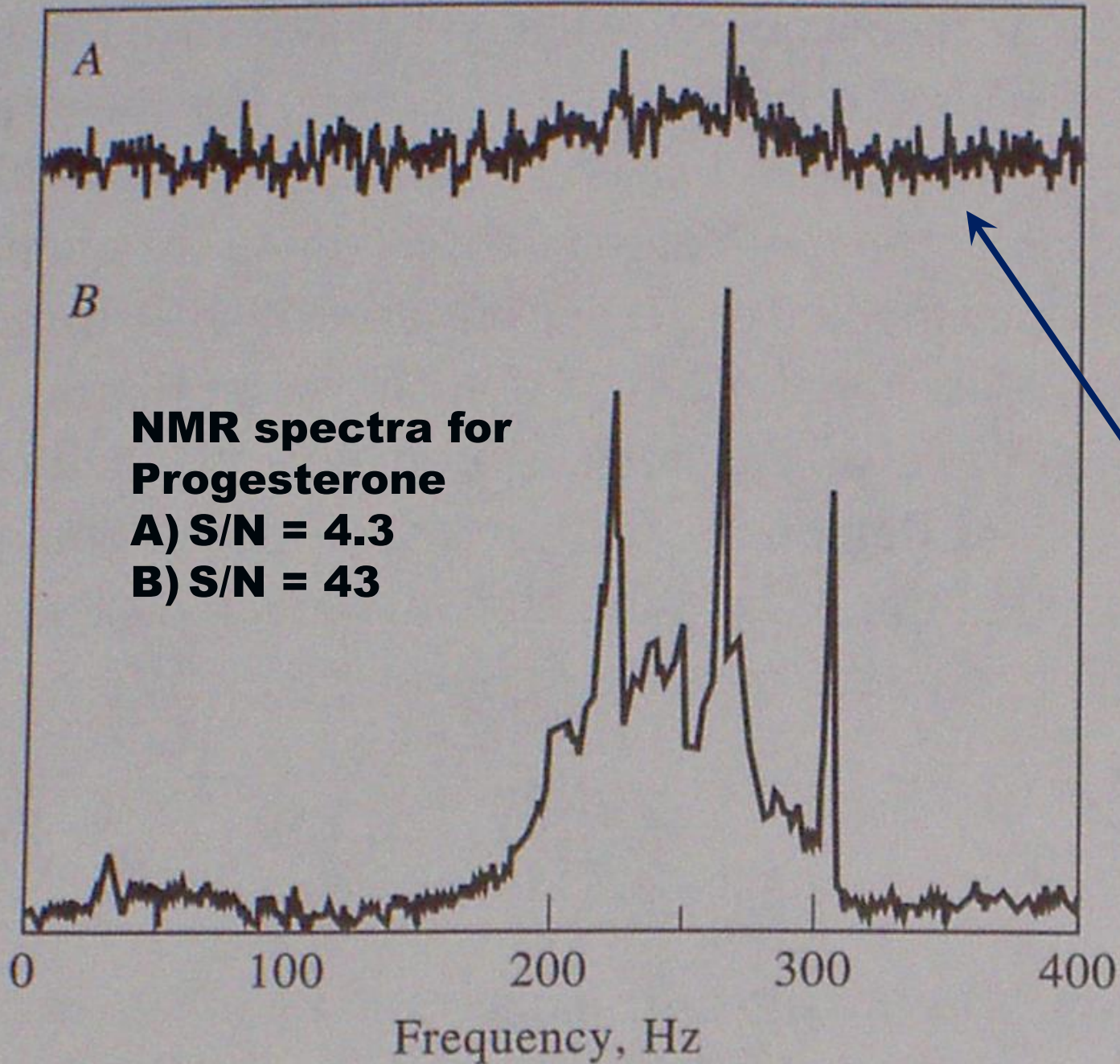
Noise is often constant and independent of signal

Signal to Noise Ratio (S/N)

- **Parameter describing quality of data**
- **Often referred to as “figure of merit”**

$$\frac{S}{N} = \frac{\text{mean of signal}}{\text{standard deviation}} = \frac{\bar{x}}{s} = \frac{1}{\text{RSD}}$$

RSD = relative standard deviation



Very little confidence in ability to determine peaks at lower S/N



Detection Limit

Sources of Noise

- **Chemical noise** – temp, pressure, humidity, etc. fluctuations = uncontrolled variables
- **Instrumental noise** – noise from instrumental components
 - **Thermal noise (Johnson noise)** – thermal motion of electrons in load resistor

$$V_{\text{rms}} = \sqrt{4 k T R \Delta f}$$

➤ Instrumental noise

- **Thermal noise**

$$V_{\text{rms}} = \sqrt{4 k T R \Delta f}$$

V_{rms} = root mean square noise voltage

k = Boltzmann constant 1.38×10^{-23} J/K

T = temperature

R = resistance

Δf = frequency bandwidth of noise

➤ Instrumental noise

- **Shot noise – movement of electrons across a junction**

$$i_{\text{rms}} = \sqrt{2 i e \Delta f}$$

i_{rms} = root-mean square current fluctuation

i = average current

e = charge on electron

Δf = frequency bandwidth

➤ **Instrumental noise**

- **Flicker noise – any noise that is inversely proportional to signal**

$$1/f$$

Significant at low frequency (<100 Hz)

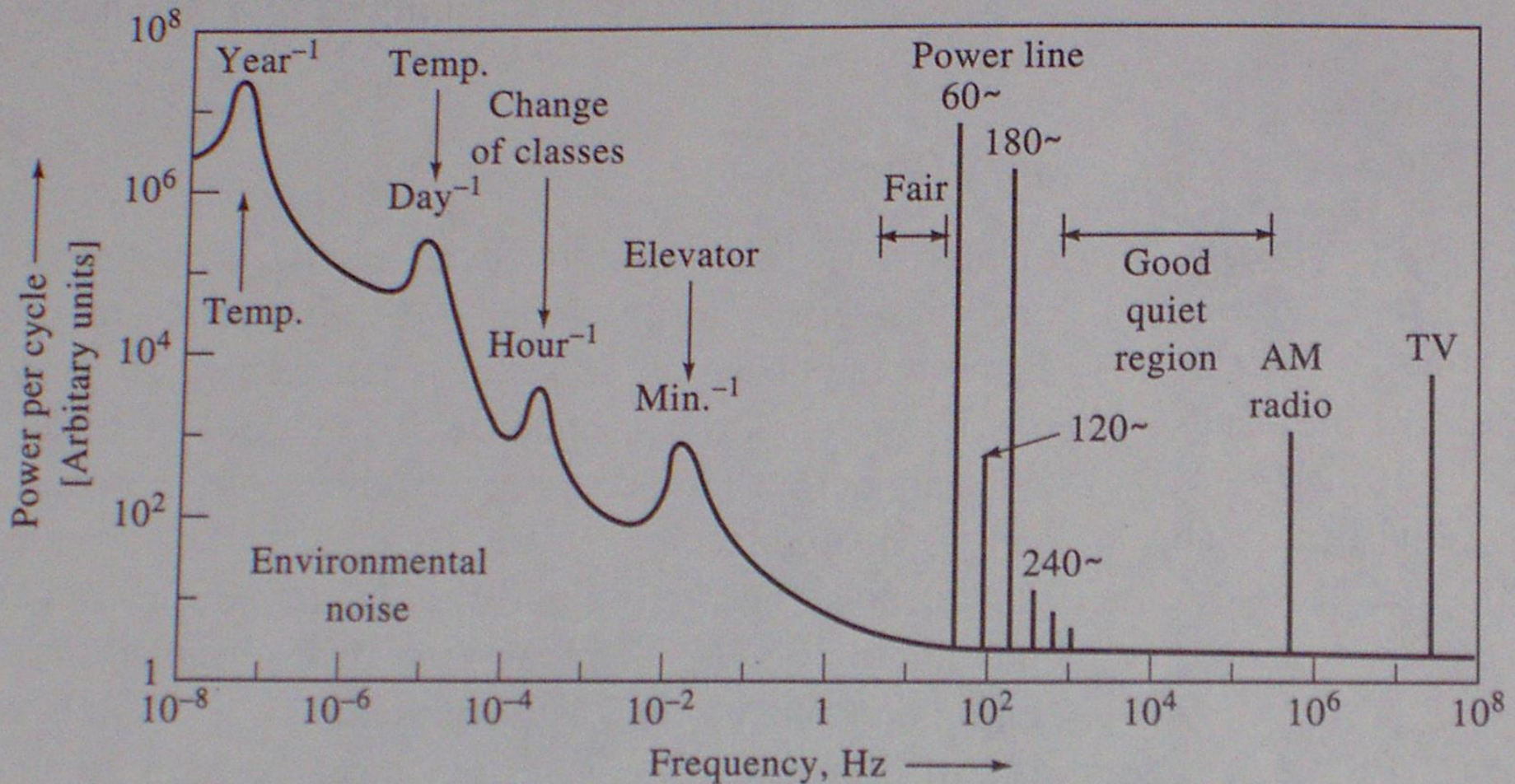
- **Environmental noise – composite of many noise sources**

e.g. any electrical device gives off EM (electromagnetic radiation)

ELF radiation = health controversy

instruments may pick up signals

Environmental noise sources (note frequency dependence)



Improving S/N

hardware & software

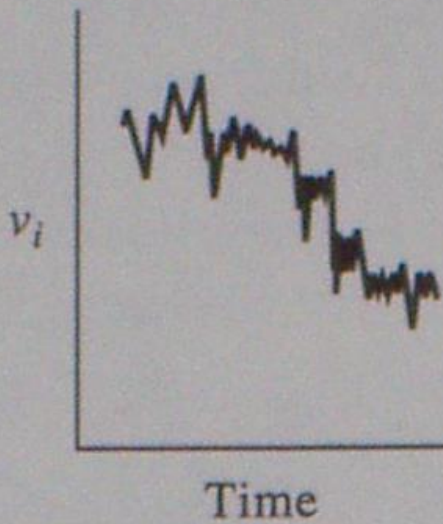
➤ Hardware

- Grounding & shielding – Faraday cage**
- Analog filtering – RC filtering**
- Modulation – convert DC signal to high frequency AC then demodulate**
- Signal chopping – rotating wheel to differentiate e.g. IR source from heat**
- Lock-in amplifiers**

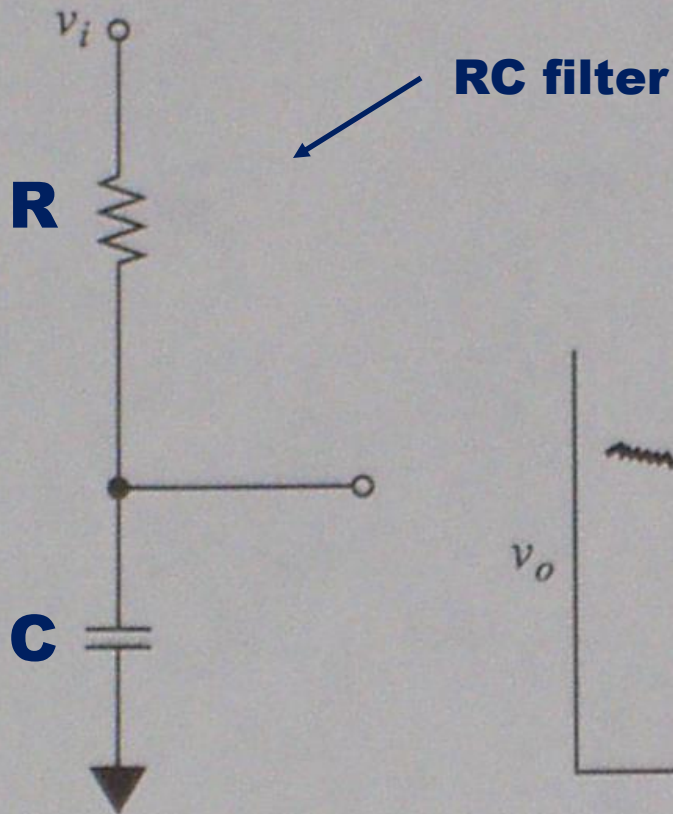


**Primitive
Faraday
Cage for
shielding
instruments
from EM
Radiation –
must be
grounded**

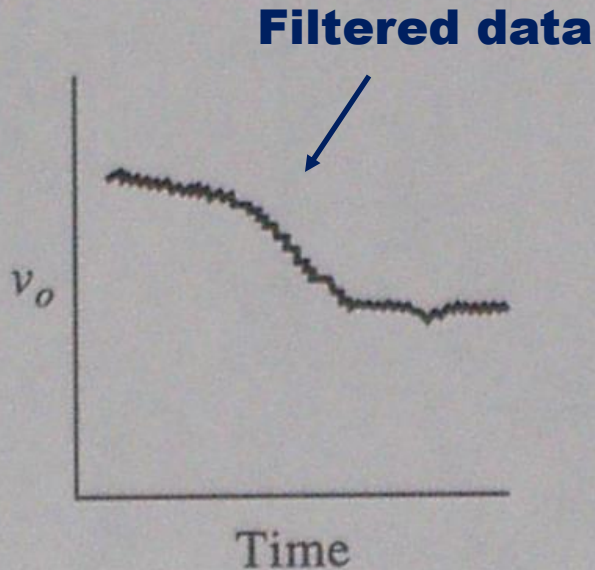
Analog Filtering or RC Filtering



Noisy data

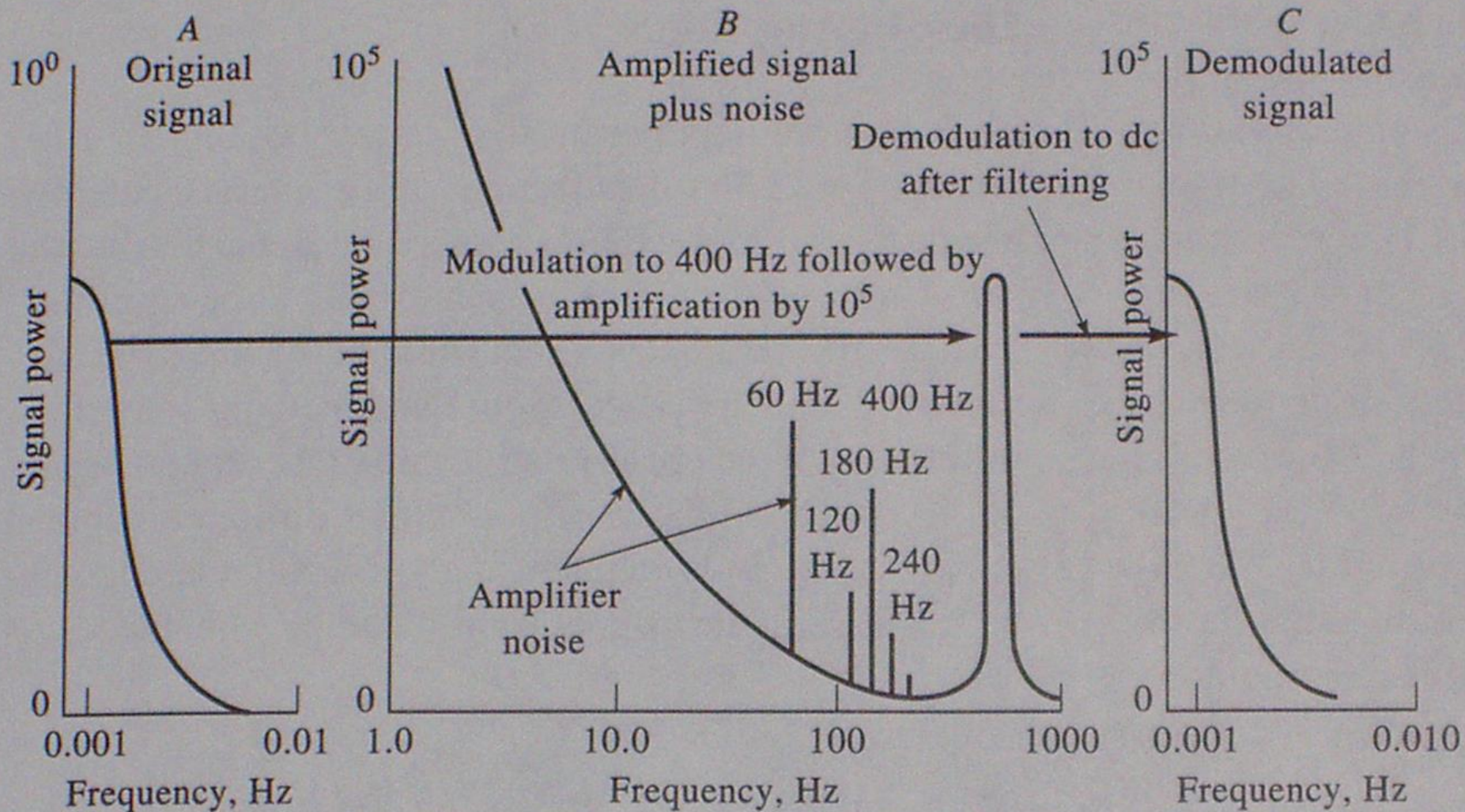


RC filter

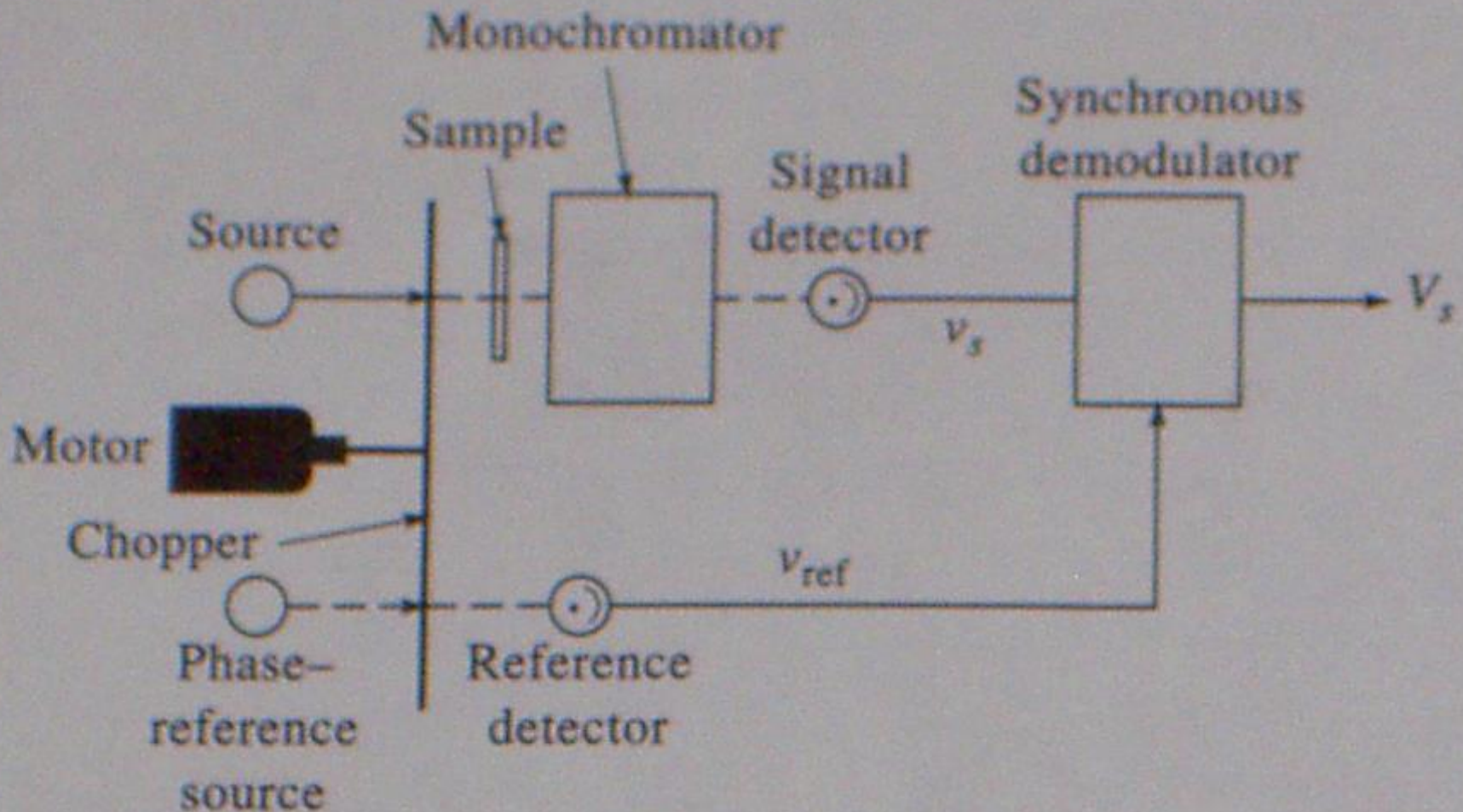


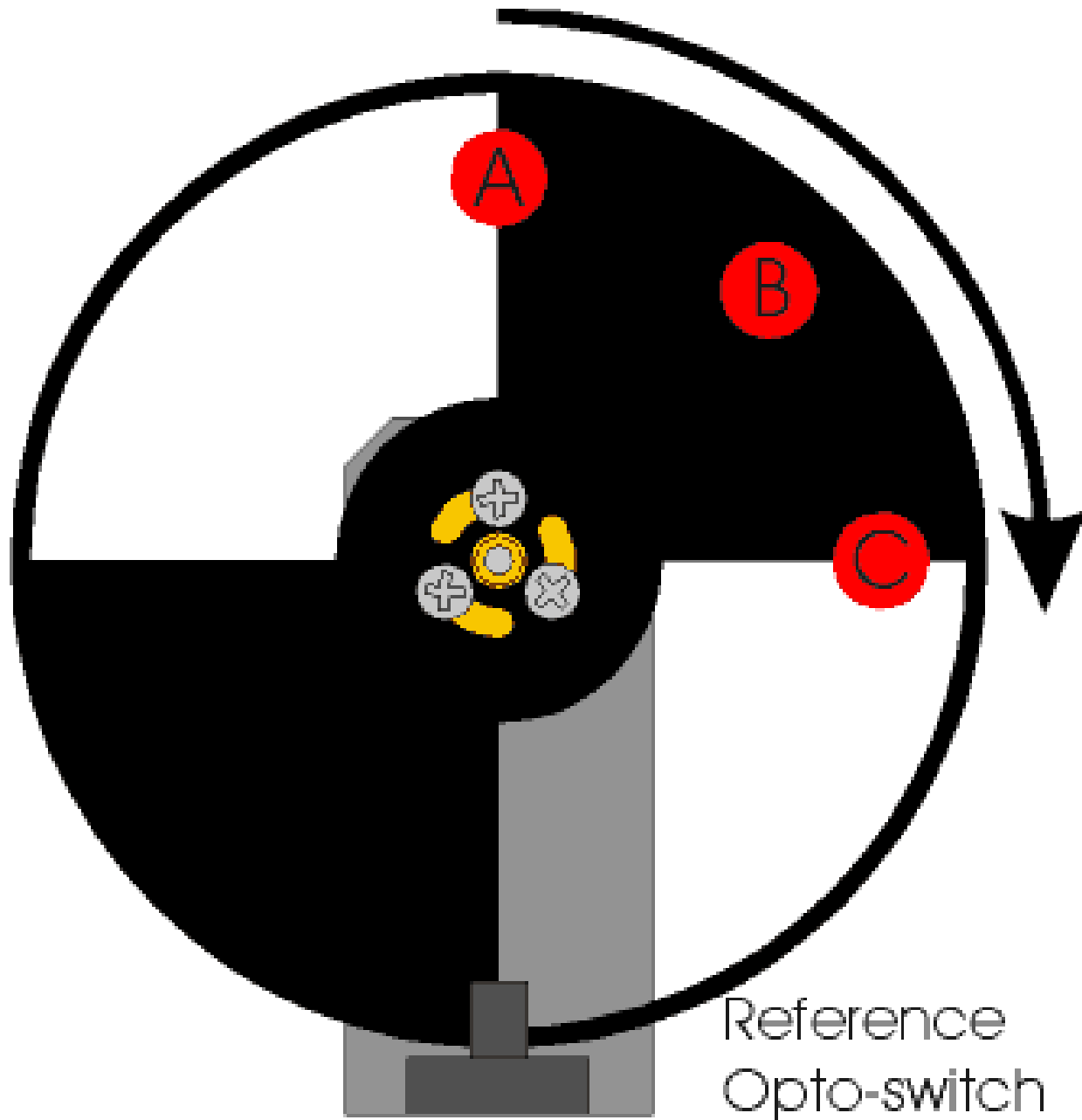
Filtered data

Modulation



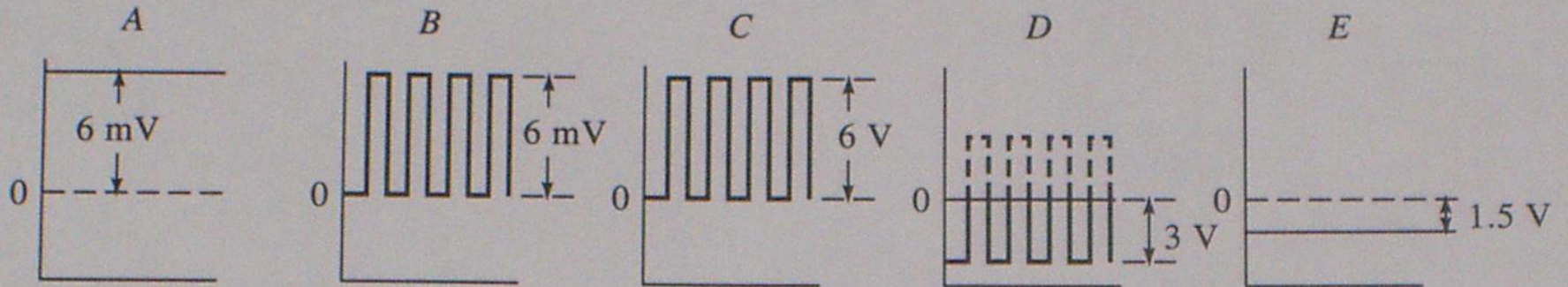
Signal chopping in an IR spectrophotometer



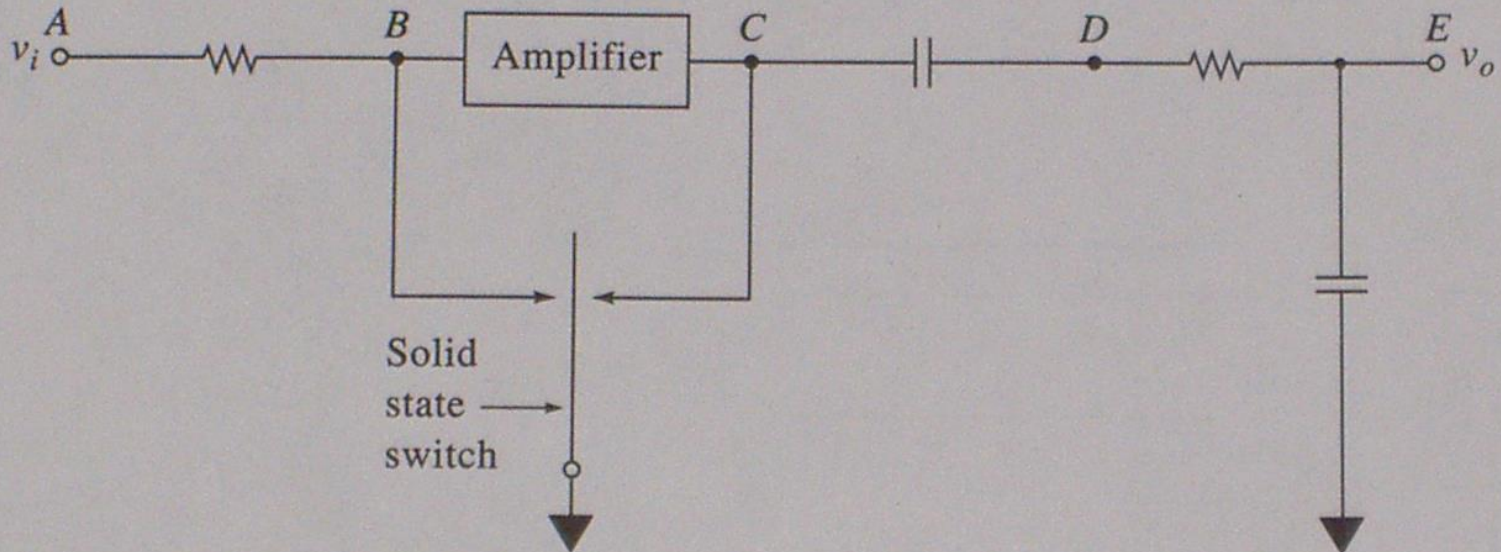


Chopper amplifier

Signal forms



Circuit

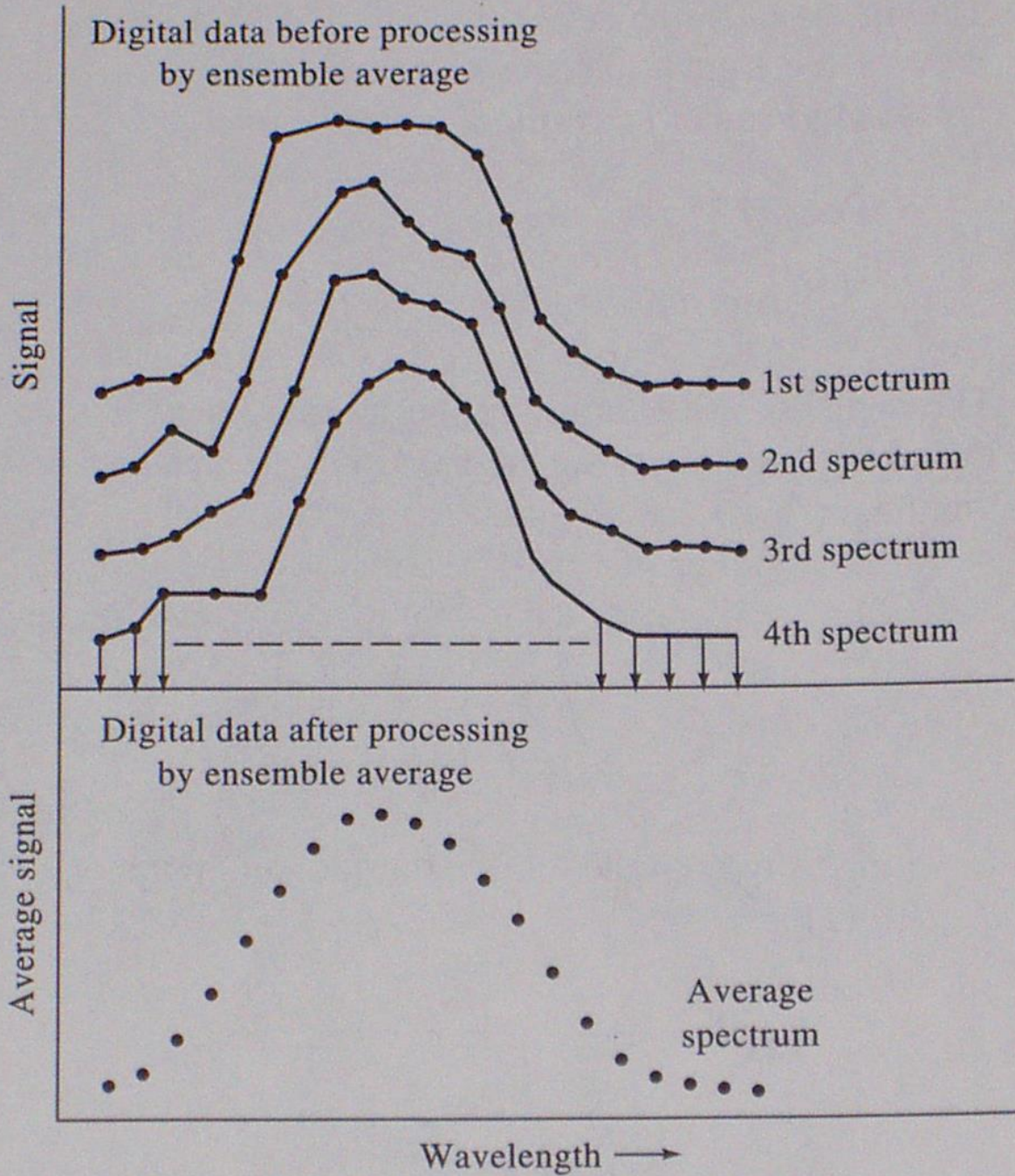


Improving S/N

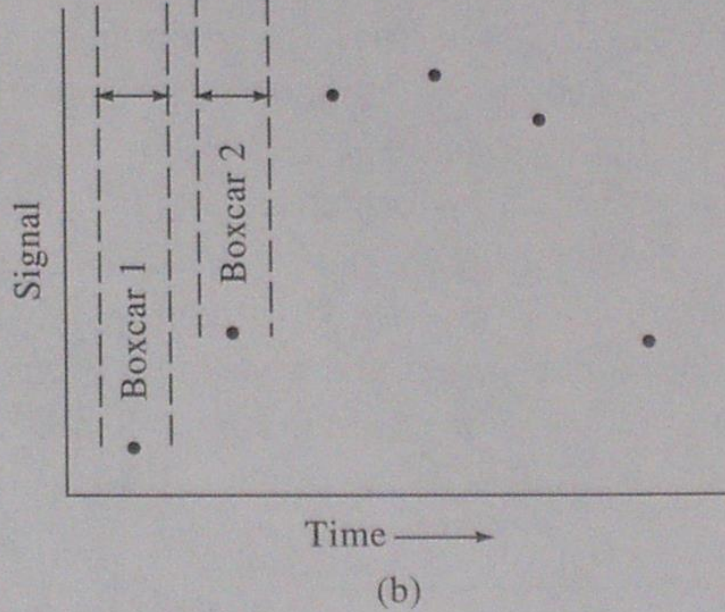
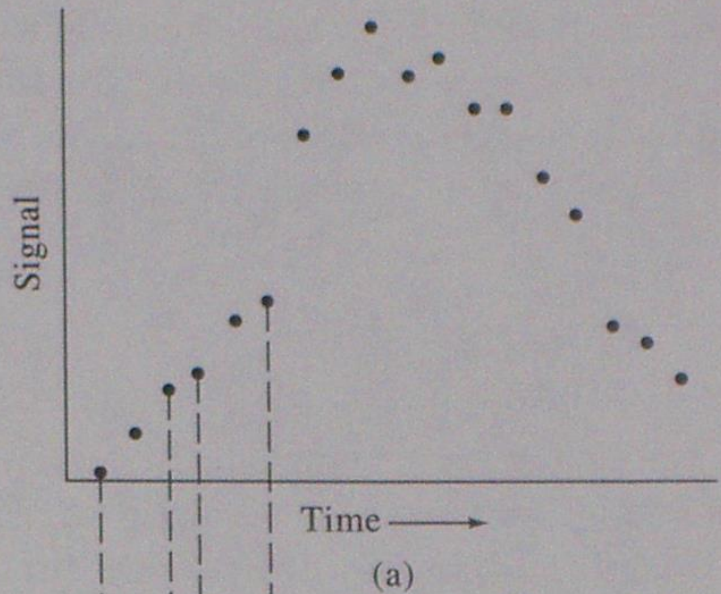
hardware & software

➤ Software

- Ensemble averaging – adding spectra**
- Boxcar averaging –**
- Digital filtering – moving window, sliding average**
- Correlation methods**



Ensemble averaging i.e. adding or averaging signal



Boxcar averaging